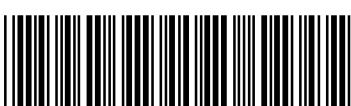


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10712341	IWASAKI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Tekle, Daniel	2621

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
386	100, 113, 125	06/09/07	D.T.

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST SEARCH DATA BASE (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	06/09/07	D.T.
COMBINED CITATION	06/09/07	D.T.
SEARCH QUERY ATTACHED	06/09/07	D.T.
INVENTOR SEARCH	06/09/07	D.T.
SEARCH UPDATED	01/21/08	D.T.
SEARCH UPDATED AND SEARCH QUERY ATTACHED	06/19/08	D.T.
SEARCH UPDATED	03/28/09	D.T.

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>